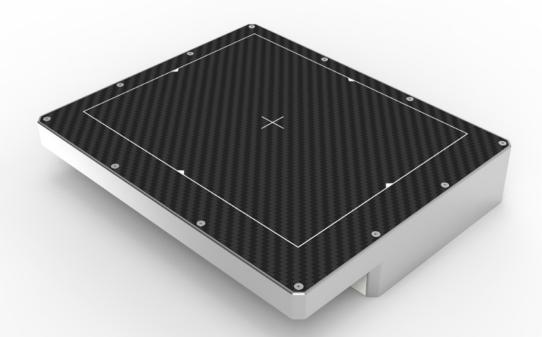
X - PANEL® 1613a FDI



Fixed a-Si-TFT X-ray flat panel detector



Key features

 Technology a-Si-TFT Pixel size 125 µm

 Pixel matrix 1024 x 1248

 Pixel area 160 x 128 mm

 Energy range 40 kVp ~ 160 kVp

Gigabit Ethernet Interface

 Frame rate 30 fps

 Applications Nondestructive testing (NDT)

Electronics inspection

Battery inspection



X-Panel 1613a FDI is a fixed type and low noise X-ray flat panel detector optimized non-destructive testing (NDT), electronics and battery inspection. It is based on amorphous silicon (a-Si) technology that features a high dynamic range and a long lifetime among other benefits.

X-Panel 1613a FDI has good image quality and a large dynamic range. Furthermore, it comes with multiple gain modes, that make it compatible with both high sensitivity and large dynamic range requirements.

Technical specifications

Technology	
Sensor	a-Si-TFT
Scintillator	GOS / CSI
Active area	160 x 128 mm
Pixel matrix	1024 x 1248
Pixel pitch	125 µm
AD conversion	16 bits

Interface		
Communication interface	Gigabit Ethernet	
Exposure control	Pulse sync in (edge or level) / Pulse sync out (edge or level)	
Modes	Software mode / HVG sync mode / FPD sync mode	
Frame Speed	30 fps	
Operating system	Windows7 / Windows10 OS 32 bits or 64 bits	

Mechanical	
Dimensions (HxWxD)	196 x 162 x 37.5 mm
Weight	1.5 kg
Sensor protection material	Carbon fiber
Housing material	Aluminum alloy

Power	
Supply	100~240 VAC
Frequency	50/60 Hz
Consumption	8 W

Environmental	
Temperature range	10~35°C (operating); -10~50°C (storage)
Humidity	30~70% RH (non-condensing)
Vibration	IEC/EN 60721-3 class 2M3 (10~150 Hz, 0.5 g)
Shock	IEC/EN 60721-3 class 2M3 (11 ms, 2 g)
Ingress protection rating	IP41

Technical performance		
Resolution	4.0 lp/mm	
Energy range	40~160 kV	
Lag	0.8% 1st frame	
Dynamic range	≥86 dB	
Sensitivity	460 lsb/μGy	
SNR	49 dB @ (20000 lsb)	
	75% @ (1 lp/mm)	
MTF	46% @ (2 lp/mm)	
	27% @ (3 lp/mm)	
DQE	58% @ (0 lp/mm)	
	43% @ (1 lp/mm)	
	30% @ (2 lp/mm)	

X-Panel 1613a FDI outline

